IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Takeshi OZEKI, et al.

U.S. Patent Application No.:

Filed: herewith

For: APPARATUS, METHOD, AND PROGRAM FOR MEASURING OPTICAL

CHARACTERISTIC USING QUANTUM INTERFERENCE, AND RECORDING

MEDIUM FOR RECORDING THE PROGRAM

PRELIMINARY AMENDMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Preliminary to examination of the above-referenced application, please amend the application as follows: